

ABSTRACT OF THE DISCLOSURE

A method and apparatus for testing a liquid crystal display device are provided to detect a defect location precisely and rapidly without requiring a jig. The method includes providing a substrate to inspect, wherein the substrate includes signal wirings, drive switches and capacitors formed in an effective display area of the substrate; radiating a light onto an inspection switch device and thereby supplying an inspection voltage from an inspection line to one of the drive switches through the signal wirings, so as to charge one of the capacitors; and determining if there is a defect in the effective display area of the substrate by reading the charged voltage of the capacitor.